



N-channel 600 V, 0.35 Ω typ., 11 A MDmesh™ M2 Power MOSFET in a TO-220FP ultra narrow leads package

Datasheet - production data

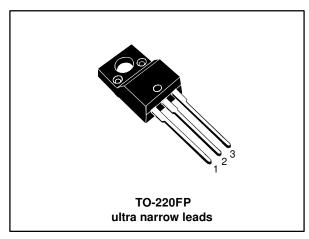
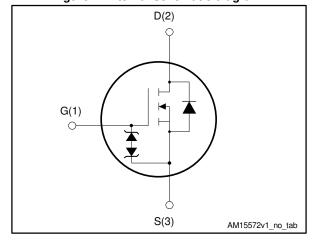


Figure 1: Internal schematic diagram



Features

Order code	V _{DS} @ T _{Jmax}	R _{DS(on)} max	ΙD
STFU13N60M2	650 V	0.38 Ω	11 A

- Extremely low gate charge
- Lower R_{DS(on)} x area vs previous generation
- Low gate input resistance
- 100% avalanche tested
- Zener-protected

Applications

• Switching applications

Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

Table 1: Device summary

Order code	Marking	Package	Packaging
STFU13N60M2	13N60M2	TO-220FP ultra narrow leads	Tube

Contents STFU13N60M2

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STFU13N60M2 Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{GS}	Gate-source voltage	± 25	V
I _D	Drain current (continuous) at T _C = 25 °C	11 ⁽¹⁾	Α
ΙD	Drain current (continuous) at T _C = 100 °C	7	Α
I _{DM} ⁽²⁾	Drain current (pulsed)	44	Α
P _{TOT}	Total dissipation at $T_C = 25$ °C	25	W
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; T_C = 25 °C)	2500	٧
dv/dt (3)	Peak diode recovery voltage slope	15	1//
dv/dt (4)	MOSFET dv/dt ruggedness	50	V/ns
T _{stg}	Storage temperature	EE to 150	°C
Tj	Max. operating junction temperature	- 55 to 150	

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	5	°C/W
R _{thj-amb}	R _{thj-amb} Thermal resistance junction-ambient max		°C/W

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax})	2.8	Α
Eas	Single pulse avalanche energy (starting $T_j = 25^{\circ}C$, $I_D = I_{AR}$; $V_{DD} = 50 \text{ V}$)	125	mJ

⁽¹⁾Limited by maximum junction temperature.

⁽²⁾Pulse width limited by safe operating area.

 $^{^{(3)}}I_{SD} \leq$ 11 A, di/dt \leq 400 A/ $\mu s;$ VDSpeak < V(BR)DSS, VDD = 400 V

 $^{^{(4)}}V_{DS} \le 480 \text{ V}$

Electrical characteristics STFU13N60M2

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 5: On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	600			٧
l	Zero gate voltage	V _{DS} = 600 V			1	μΑ
I _{DSS}	drain current $(V_{GS} = 0)$	V _{DS} = 600 V, T _C = 125 °C			100	μΑ
Igss	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 25 V			±10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS}=V_{GS},I_D=250\;\mu A$	2	3	4	٧
R _{DS(on)}	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_{D} = 5.5 \text{ A}$		0.35	0.38	Ω

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		1	580	-	pF
Coss	Output capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz},$ $V_{GS} = 0 \text{ V}$	1	32	-	pF
C_{rss}	Reverse transfer capacitance			1.1	-	pF
C _{oss eq.} (1)	Equivalent output capacitance V _{DS} = 0 to 480 V, V _{GS} = 0 V		-	120	-	pF
Rg	Intrinsic gate resistance f = 1 MHz open drain		1	6.6	-	Ω
Q_g	Total gate charge $V_{DD} = 480 \text{ V}, I_D = 11 \text{ A},$		1	17	-	nC
Q_{gs}	Gate-source charge	V _{GS} = 10 V (see Figure 15: "Test circuit for gate charge		2.5	-	nC
Q_{gd}	Gate-drain charge	behavior")	-	9	-	nC

Notes:

4/12

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 5.5 \text{ A},$	ı	11	1	ns
tr	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$ (see Figure 14: "Test circuit	-	10	-	ns
t _{d(off)}	Turn-off delay time	for resistive load switching	-	41	-	ns
t _f	Fall time	times" and Figure 19: "Switching time waveform")	-	9.5	-	ns

 $^{^{(1)}}C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 8: Source drain diode

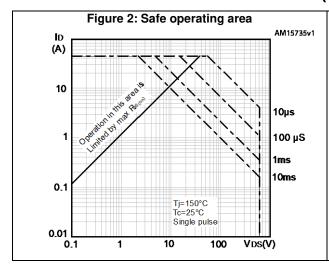
Symbol	Parameter Test conditions		Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		11	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		44	Α
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 11 A, V _{GS} = 0 V	-		1.6	V
t _{rr}	Reverse recovery time	$I_{SD} = 11 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s},$	-	297		ns
Qrr	Reverse recovery charge	V _{DD} = 60 V (see Figure 16: "Test circuit for inductive load	-	2.8		μC
I _{RRM}	Reverse recovery current	switching and diode recovery times")	ı	18.5		Α
t _{rr}	Reverse recovery time	$I_{SD} = 11 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	394		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150 \text{ °C}, \text{ (see }$ Figure 16: "Test circuit for	-	3.8		μC
I _{RRM}	Reverse recovery current	inductive load switching and diode recovery times")	-	19		Α

Notes:

 $^{^{(1)}}$ Pulse width limited by safe operating area.

 $^{^{(2)}}$ Pulsed: pulse duration = 300 μ s, duty cycle 1.5%.

2.1 Electrical characteristics (curves)



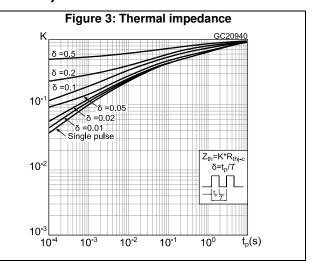


Figure 4: Output characteristics

AM15712v1

AM15712v1

AM15712v1

AM15712v1

AM15712v1

AW15712v1

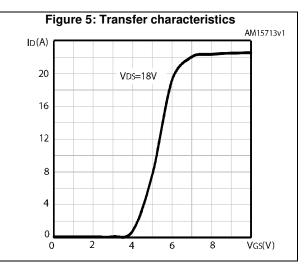


Figure 6: Normalized V(BR)DSS vs temperature

V(BR)DSS
(nom)

1.1

1.06

1.02

0.98

0.94

0.9

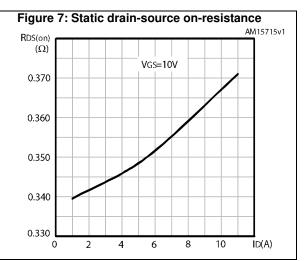
-50

0

50

100

TJ(°C)



STFU13N60M2 Electrical characteristics

Figure 8: Gate charge vs gate-source voltage VDS (V) VDD=480V VDS 500 10 ID=11A 400 8 300 6 200 2 100 0 12 Qg(nC) 8 16

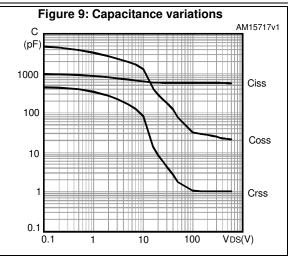


Figure 10: Normalized gate threshold voltage vs temperature

VGS(th)

1.1

1.0

0.9

0.8

0.7

0.6

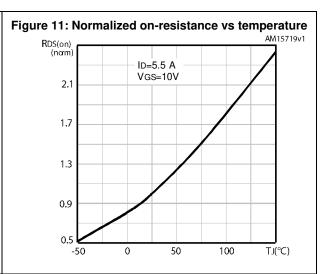
-50

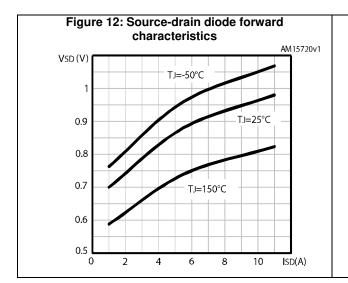
0

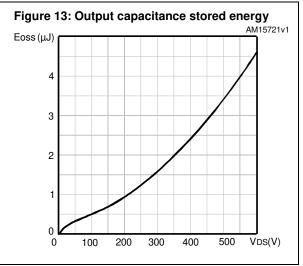
50

100

TJ(°C)







Test circuit STFU13N60M2

3 Test circuit

Figure 14: Test circuit for resistive load switching times

Figure 15: Test circuit for gate charge behavior

12 V 47 kΩ 100 nF 1 kΩ

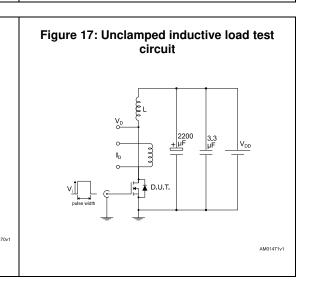
Vos 1 1 kΩ

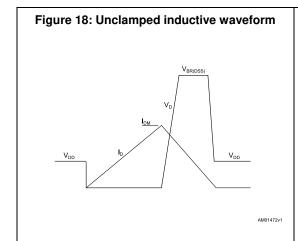
Vos 1 1 kΩ

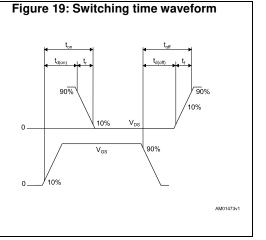
Vos 1 1 kΩ

AM01468v1

Figure 16: Test circuit for inductive load switching and diode recovery times







4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

4.1 TO-220FP package information

F1(x3)D G1 Ε 8576148_1

Figure 20: TO-220FP ultra narrow leads package outline

Table 9: TO-220FP ultra narrow leads mechanical data

	2010 0. 10 22011 untu nui	mm	
Dim.	Min.	Тур.	Max.
Α	4.40		4.60
В	2.50		2.70
D	2.50		2.75
E	0.45		0.60
F	0.65		0.75
F1	-		0.90
G	4.95		5.20
G1	2.40	2.54	2.70
Н	10.00		10.40
L2	15.10		15.90
L3	28.50		30.50
L4	10.20		11.00
L5	2.50		3.10
L6	15.60		16.40
L7	9.00		9.30
L8	3.20		3.60
L9	-		1.30
Dia.	3.00		3.20

STFU13N60M2 Revision history

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
09-Mar-2015	1	Initial release
15-Sep-2015	2	Document status changed from preliminary to production data.

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